Application/Control No. 10/028,145 Examiner Christopher Verdier Applicant(s)/Patent Under Reexamination LEE ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name .	Classification
	Α	US-3423069-A	01-1969	Chandley	416/92
	В	US-4501053-A	02-1985	Craig et al.	416/97R
	С	US-6164914-A	12-2000	Correia et al.	416/97R
	D	US-5733102-A	03-1998	Lee et al.	416/97R
	Ε	US-6224336-B1	05-2001	Kercher	416/97R
	F	US-2002/0187044-A1	12-2002	Lee et al.	416/97R
	G	US-6224337-B1	05-2001	Lieland et al.	416/97R
	π	US-			
	-	US-			,
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N	JP-1-53002-A	03-1989	Japan		416/95	
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	Р						
	Q						
	R						
	s						
	Т				, 10 to 10 t		

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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